



IECQ QUALITY ASSESSMENT SYSTEM (IECQ)

For rules and details of the IECQ visit www.iecq.org

IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.:	IECQ-L DEKRA 16.0002-02	Issue No.:	5	Status:	Draft
Additional Site to Certification: IECQ-L DEKRA 16.0002		Originally Issued: 2016/08/17			
Supersedes:	IECQ-L DEKRA 16.0002-02 Issue 4	Issue Date:	2025/07/20	Site Added:	2017/12/22
CB Reference No.:	DEKRA-T5C-003	Expiration:	2028/07/19		

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The organization, facilities and procedures have been assessed by the IECQ Certification Body in accordance with IECQ 03-1 and IECQ 03-6 for issuance of this certificate and found to be in conformity with the applicable requirements of the IECQ Independent Testing Laboratory Assessment Program Requirements Scheme and in respect of ISO/IEC 17025:2017 for the testing of component product under the IECQ.

Scope:

Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

See attached Schedule of Scope

-- Attached Schedule: IECQ-L DEKRA 16.0002-02-S.pdf --

Approved by Certification Body (CB): DEKRA Certification B.V.

Meander 1051
Arnhem
Netherlands

Authorized person:
Ted Gaertner



The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.

This Certificate of Conformity may be suspended or withdrawn in accordance with the Rules of Procedure of the IECQ System and its Schemes.

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Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L DEKRA 16.0002-02

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Schedule Number: IECQ-L DEKRA 16.0002-02-S Rev No.: 5 Revision Date: 2025/07/20 Page 1 of 1

Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

Description test	Standard
Steady-Status Temperature and Humidity Bias Life Test (THB)	JESD22-A101, AEC-Q100, AECQ-101, AEC-Q200, MIL-STD-202
High Humidity High Temp. Reverse Bias (H3TRB)	JESD22-A101, AEC-Q101
Power and Temperature Cycling (PTC)	JESD22-A105, AEC-Q100, AEC-Q101
High Temperature Operation test (HTOL)	JESD22-A108, AEC-Q100, AEC-Q200, MIL-STD-202
Low Temperature Operation test (LTOL)	JESD22-A108
High Temperature Reverse Bias (HTRB)	JESD22-A108, AEC-Q101, MIL-STD-750, MIL-STD-883
High Temperature Gate Bias (HTGB)	JESD22-A108, AEC-Q101
Early Life Failure Rate (ELFR)	JESD22-A108, AEC-Q100
Highly Accelerated Stress Test (HAST)	JESD22-A110, AEC-Q100, AEC-Q101
Electrically Erasable Programmable ROM (EEPROM) Program/Erase Endurance and Data Retention Stress Test (Endurance and Data Retention)	JESD22-A117, AEC-Q100,
Power Cycling	JESD22-A122
NVM Endurance, Data Retention, and Operation Life (EDR)	AEC-Q100
Electromigration (EM)	JEP001, JESD61, JESD87, AEC-Q100,
Stress Migration (SM)	JEP001, JEP139, JESD87, AEC-Q100,
Steady-Status operation life	MIL-STD-750, MIL-STD-883
Wafer/Substrate saw	A00-550-30001
Die Bond	A00-550-30034
Wire Bonding	A00-550-30003 A00-550-30035

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